

Search Notes

Application/Control No.

10/026,618

Examiner

Emmanuel Bayard

Applicant(s)/Patent under
Reexamination

LEE ET AL.

Art Unit

2611

SEARCHED

Class	Subclass	Date	Examiner
375	316	5/16/2007	EB
375	326	5/16/2007	EB
375	327	5/16/2007	EB
375	340	5/16/2007	EB
375	324	5/16/2007	EB
375	344	5/16/2007	EB
375	345	5/16/2007	EB
375	354	5/16/2007	EB

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
375	354	5/16/2007	EB
375	316	5/16/2007	EB

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East	5/16/2007	EB